

May 2009

# FDMS8848NZ

# N-Channel PowerTrench® MOSFET 40 V, 49 A, 3.1 m $\Omega$

### **Features**

- Max  $r_{DS(on)}$  = 3.1 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 22.8 A
- Max  $r_{DS(on)}$  = 5.1 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 17.5 A
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- MSL1 robust package design
- RoHS Compliant

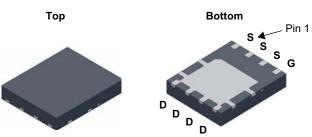


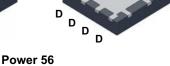
## **General Description**

The FDMS8848NZ has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest r<sub>DS(on)</sub> while maintaining excellent switching performance.

## **Applications**

- Computing VR & IMVP Vcore
- Secondary Side Synchronous Rectifier
- POL DC/DC Converter
- Oring FET/ Load Switching





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**MOSFET Maximum Ratings** T<sub>C</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			40	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		49	
	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		143	٦ ,
l <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	22.8	- A
	-Pulsed			90	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	480	mJ
Б	Power Dissipation	T <sub>C</sub> = 25 °C		104	w
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8848NZ	FDMS8848NZ	Power 56	13"	12 mm	3000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted Parameter

Off Characteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	40			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		28		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32 V, V <sub>GS</sub> = 0 V			1	μА
IGSS	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА

**Test Conditions** 

Min

Тур

Max

Units

### On Characteristics

Symbol

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	1.7	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		-6		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 22.8 A		2.6	3.1	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 17.5 A		3.3	5.1	mΩ
	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 22.8 A, T <sub>J</sub> = 125 °C		3.8	5.3		
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 22.8 A		130		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	v 00 V V 0 V	6071	8075	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V, f = 1 MHz	705	940	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	466	700	pF
$R_g$	Gate Resistance		1.4	2.8	Ω

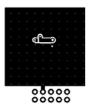
## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				20	36	ns
t <sub>r</sub>	Rise Time		$V_{DD}$ = 20 V, $I_{D}$ = 22.8 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		19	35	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10 V, R <sub>GEN</sub> =			63	101	ns
t <sub>f</sub>	Fall Time				13	24	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V			108	152	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 5 V	V <sub>DD</sub> = 20 V,		57	80	nC
Q <sub>gs</sub>	Gate to Source Charge		$I_D = 22.8 \text{ A}$		17		nC
$Q_{gd}$	Gate to Drain "Miller" Charge				19		nC

### **Drain-Source Diode Characteristics**

V		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)		0.7	1.2	V
V <sub>SD</sub>		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 22.8 A (Note 2)		0.8	1.3	
t <sub>rr</sub>	Reverse Recovery Time	L = 22.8 A di/dt = 100 A/		34	55	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 22.8 A, di/dt = 100 A/μs		28	45	nC

1.  $R_{\theta,JA}$  is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta,JC}$  is guaranteed by design while  $R_{\theta,CA}$  is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3. Starting T  $_{\rm J}$  = 25°C, L =1 mH, I  $_{\rm AS}$  = 31 A, V  $_{\rm DD}$  = 36 V, V  $_{\rm GS}$  = 10 V

### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

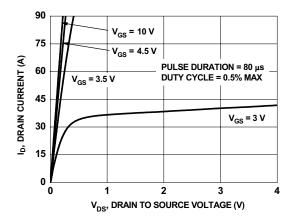


Figure 1. On Region Characteristics

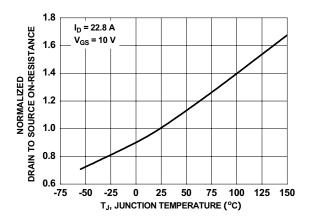


Figure 3. Normalized On Resistance vs Junction Temperature

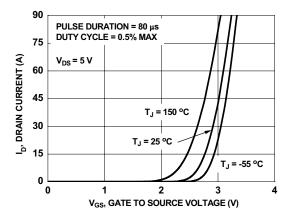


Figure 5. Transfer Characteristics

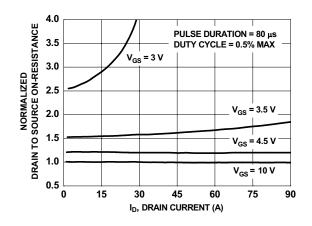


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

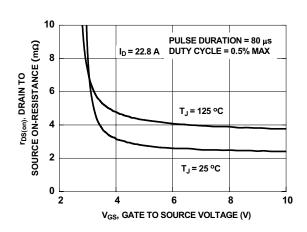


Figure 4. On-Resistance vs Gate to Source Voltage

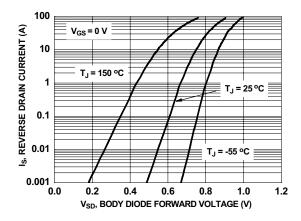


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

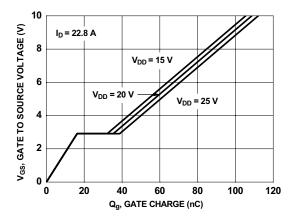


Figure 7. Gate Charge Characteristics

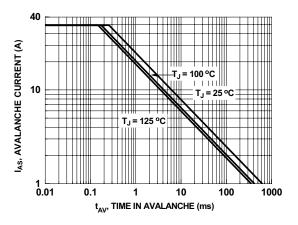


Figure 9. Unclamped Inductive Switching Capability

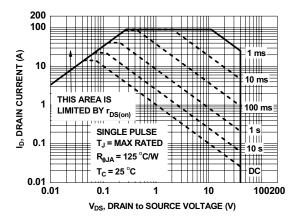


Figure 11. Forward Bias Safe Operating Area

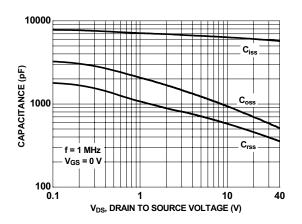


Figure 8. Capacitance vs Drain to Source Voltage

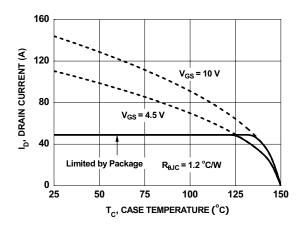


Figure 10. Maximum Continuous Drain Current vs Case Temperature

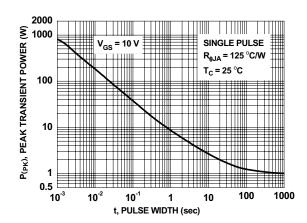


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

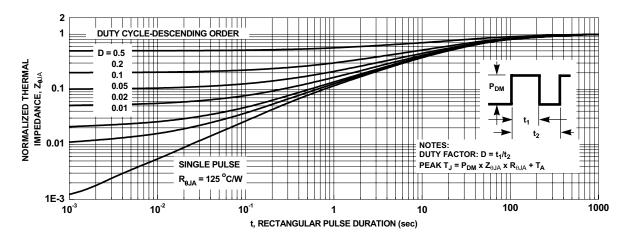
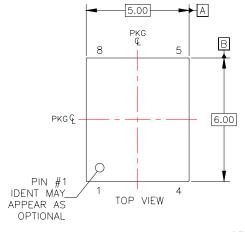
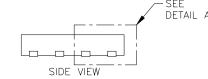
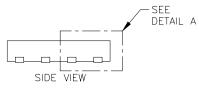


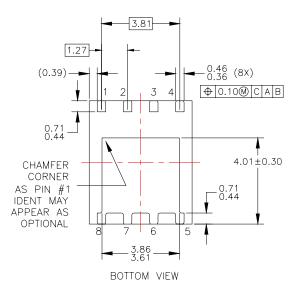
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

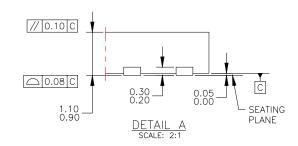
# **Dimensional Outline and Pad Layout**

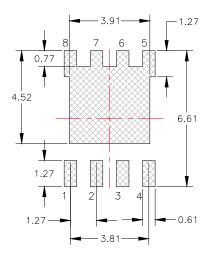




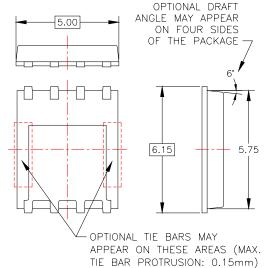








LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA, DATED OCTOBER 2002.
- ALL DIMENSIONS ARE IN MILLIMETERS.
- DIMENSIONS ARE IN MILLIMETERS.
  DIMENSIONS DO NOT INCLUDE BURRS
  OR MOLD FLASH. MOLD FLASH OR
  BURRS DOES NOT EXCEED 0.10MM.
  DIMENSIONING AND TOLERANCING PER
  ASME Y14.5M-1994.
  DRAWING FILE NAME: PQFN08AREV4





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